

Notice of Allowability

Application No.

10/730,106

Examiner

Zia R. Hashmi

Applicant(s)

SUZUKI ET AL.

Art Unit

2881

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to 6/29/2005.
2. ☒ The allowed claim(s) is/are 1, 3, 5 and 6.
3. ☒ The drawings filed on 09 December 2003 are accepted by the Examiner.
4. ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☒ All b) ☐ Some* c) ☐ None of the:
 1. ☒ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
6. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.

Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
7. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

- | | |
|---|---|
| 1. <input type="checkbox"/> Notice of References Cited (PTO-892) | 5. <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 2. <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 6. <input type="checkbox"/> Interview Summary (PTO-413),
Paper No./Mail Date _____ |
| 3. <input checked="" type="checkbox"/> Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date <u>12/9/2003</u> | 7. <input type="checkbox"/> Examiner's Amendment/Comment |
| 4. <input type="checkbox"/> Examiner's Comment Regarding Requirement for Deposit
of Biological Material | 8. <input checked="" type="checkbox"/> Examiner's Statement of Reasons for Allowance |
| | 9. <input type="checkbox"/> Other _____ |

DETAILED ACTION

Allowable Subject Matter

1. An "Amendment" was received on June 29, 2005, in response to Office Action of December 29, 2004. Independent claims 1, 3 & 5 have been amended and claims 2 & 4 have been canceled, as indicated.
2. Claims 1, 3-4 and 5 are allowed.
3. Then following is an examiner's statement of reasons for allowance:
4. With respect to independent claims 1 and 3, prior art fails to disclose in combination with other recited limitations of the claims, a scanning electron microscope comprising: an electron source for generating an electron beam; a magnetic field type object lens for focusing the electron beam; a detector arranged on an electron source side of a focused magnetic field of the object lens; a negative voltage applying power source applying a negative voltage to a sample, the object lens being formed for leaking a magnetic field toward a sample side, said detector or a conductor plate emitting a secondary electron by collision of a reflected electron being arranged in a direction toward which said reflected electron emitted from said sample in a direction other than an opening of said object lens for passing said electron beam is deflected by an electric field formed between the sample and the object lens, or the accelerating tube, and the leaking magnetic field, wherein a plurality of detectors are arranged at positions in axial symmetry with respect to an optical axis of the electron beam.

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5. With respect to independent claim 5, prior art fails to disclose a sample image forming method forming a sample image based electron generated by scanning an electron beam focused by an object lens on a sample, comprising: deflecting a track of a reflected electron reflected by a tilted portion on said sample toward a center of said object lens by forming a focused magnetic field in a region including said sample; deflecting the track of the reflected electron reflected by the tilted portion of said sample toward said object lens by forming an electric field between said sample and said object lens; and detecting said reflected electron passed through said object lens with a plurality of detectors arranged at positions in axial symmetry with respect to an optical axis of said electron beam.

Claim 6 is allowed by virtue of its dependency on the independent claim 5.

Conclusion

6. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments of Statement of Reasons for Allowance".

7. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you

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have questions on access to the Private PAIR system, contact Electronic Business Center (EBC) at 866-217-9197 (toll-free).

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Zia Hashmi whose telephone number is (571) 272-2473.

The examiner can normally be reached between 8.30 AM- 5 PM. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John R. Lee can be reached on (571) 272-2477.

Zia Hashmi

July 28, 2005


NIKITA WELLS
PRIMARY EXAMINER 07/28/05